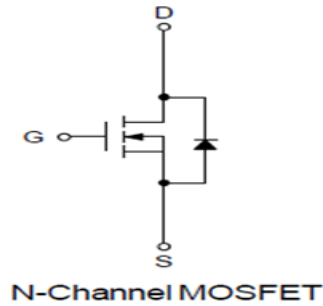


POWER MOSFET

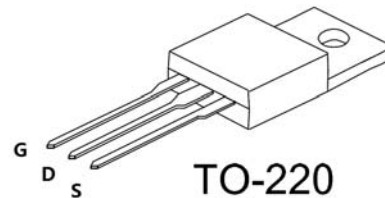
Features

- 150V,80A N-Channel MOSFET
- $R_{DS(on)(typ.)}=17m\Omega @V_{GS}=10V$
- High ruggedness
- Fast switching
- 100% avalanche tested
- Exceptional dv/dt capability



Applications

- Switching application
- Motor drive



Absolute Maximum Ratings

Symbol	Parameter	Value	Units
V_{DSS}	Drain-Source Voltage	150	V
V_{GS}	Gate-Source Voltage	± 25	V
I_D	Continuous Drain Current($T_C=25^{\circ}C$)	80	A
	Continuous Drain Current($T_C=100^{\circ}C$)	70	A
I_{DM}	Pulsed Drain Current(Note 1)	300	A
EAS	Single Pulsed Avalanche Energy(Note 2)	400	mJ
P_D	Maximum Power Dissipation ($T_C=25^{\circ}C$)	176	W
	Maximum Power Dissipation ($T_C=100^{\circ}C$)	90	W
T_J	Maximum Junction Temperature	175	$^{\circ}C$
T_{STG}	Storage Temperature Range	-55 to +175	$^{\circ}C$

Notes:

1. Repetitive Rating: Pulse width limited by maximum junction temperature

2.Starting $T_J=25^{\circ}C, L=1.0mH, R_G=25\Omega, I_D=37A, V_{GS}=10V$

Thermal data

Symbol	Parameter	Max.	Units
$R_{th\ J-C}$	Thermal Resistance, Junction to case	0.45	$^{\circ}C/W$

Electrical Characteristics (TC=25 $^{\circ}C$ unless otherwise noted)

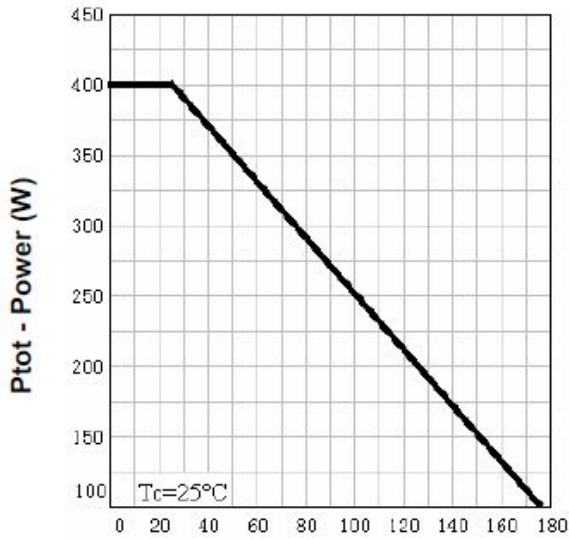
Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=250\mu A$	150			V
I_{DSS}	Drain-Source Leakage Current	$V_{DS}=100V, V_{GS}=0V$			1	μA
I_{GSS}	Gate Leakage Current, Forward	$V_{GS}=25V, V_{DS}=0V$			100	nA
	Gate Leakage Current, Reverse	$V_{GS}=-25V, V_{DS}=0V$			-100	nA
$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS}=V_{DS}, I_D=250\mu A$	2	3	4	V
$R_{DS(on)}$	Collector-Emitter Saturation Voltage	$V_{GS}=10V, I_D=40A$		17	20	m Ω
gfs	Forward Transconductance	$V_{DS}=15V, I_D=40A$		25		S
Q_g	Total Gate Charge	$V_{DS}=30V$ $V_{GS}=10V$ $I_D=40A$		170	240	nC
Q_{gs}	Gate-Source Charge			55		nC
Q_{gd}	Gate-Drain Charge			60		nC
$t_{d(on)}$	Turn-on Delay Time	$V_{DD}=35V, R_L=35\Omega$ $V_{GEN}=10V$ $I_D=1A$ $R_G=6\Omega$	-	26	-	ns
t_r	Turn-on Rise Time		-	46	-	ns
$t_{d(off)}$	Turn-off Delay Time		-	129	-	ns
t_f	Turn-off Fall Time		-	88	-	ns
C_{iss}	Input Capacitance	$V_{DS}=30V$ $V_{GS}=0V$ $f=1MHz$	-	6900	-	pF
C_{oss}	Output Capacitance		-	1100	-	pF
C_{rss}	Reverse Transfer Capacitance		-	519	-	pF
R_{Gint}	Integrated gate resistor			1.05		Ω

Source-Drain Ratings and Characteristics (TC=25 $^{\circ}C$ unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
V_{SD}	Forward On Voltage	$V_{GS}=0V, I_{SD}=60A$	-	0.8	1.3	V
I_S	Continuous Diode Forward Current				130	A
t_{rr}	Reverse Recovery Time	$I_{SD}=60A$ $dI_F/dt=100A/\mu s$	-	68		ns
Q_{rr}	Reverse Recovery Charge		-	130		nC

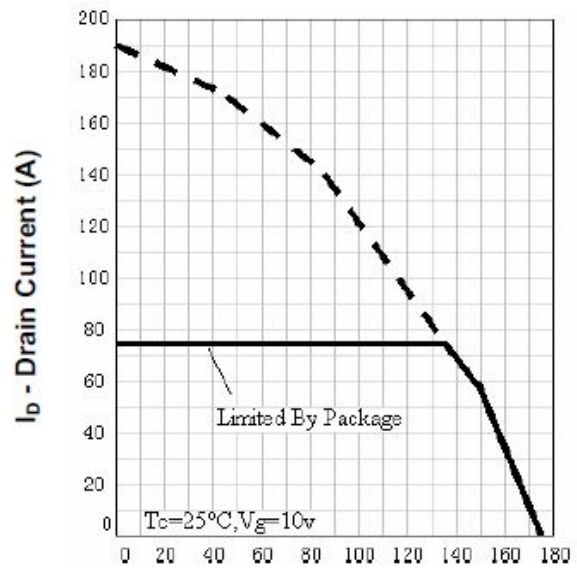
Typical Characteristics

Power Dissipation



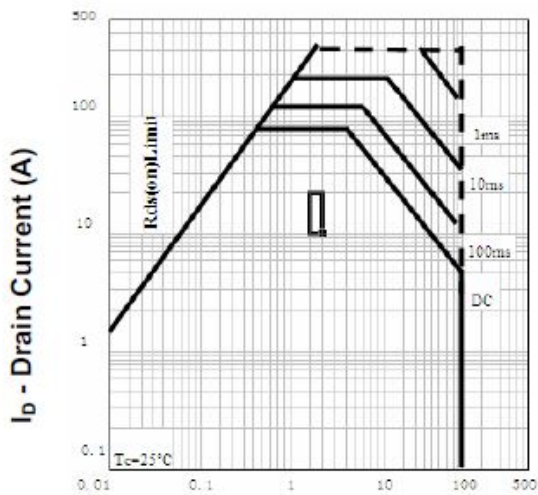
T_j - Junction Temperature (°C)

Drain Current



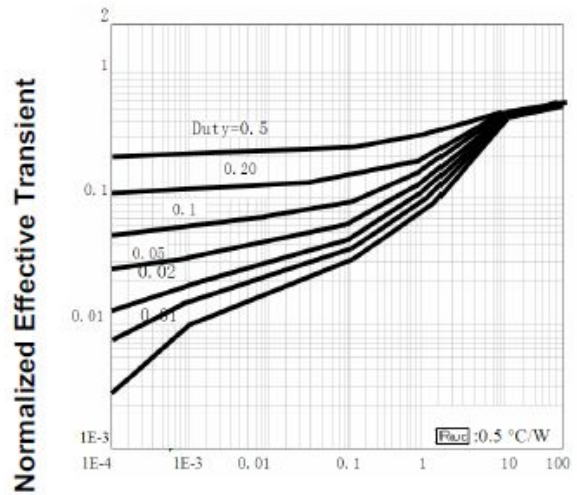
T_j - Junction Temperature (°C)

Safe Operation Area



V_{DS} - Drain-Source Voltage (V)

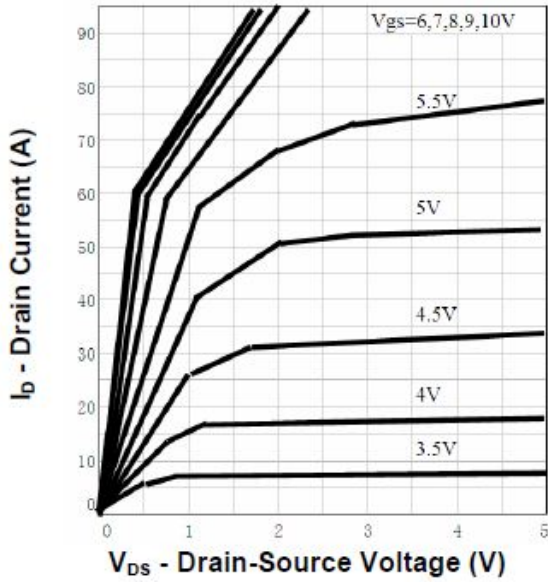
Thermal Transient Impedance



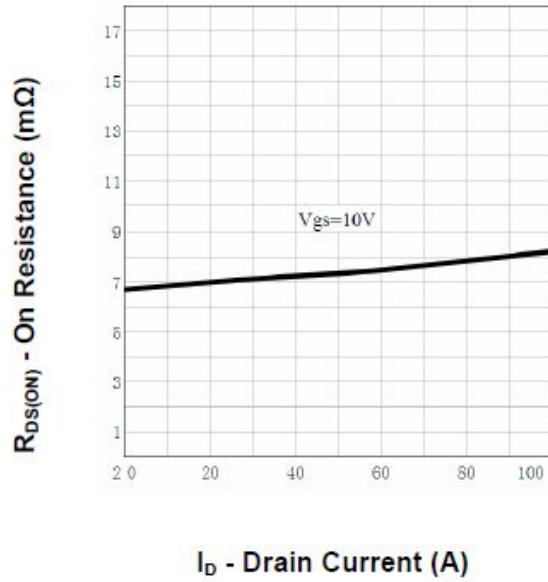
Square Wave Pulse Duration (sec)

Typical Characteristics

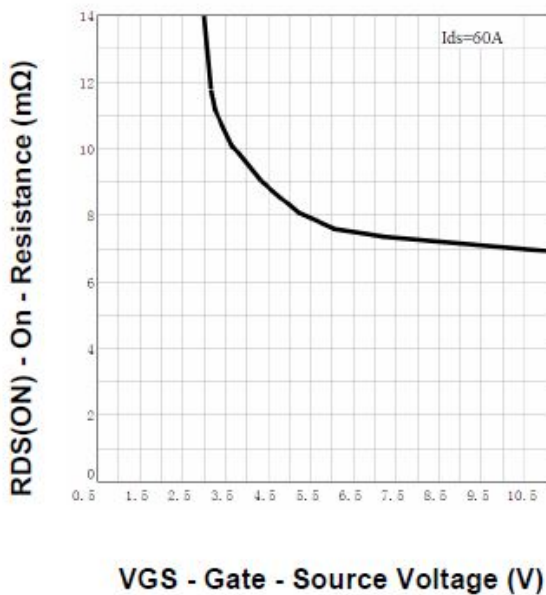
Output Characteristics



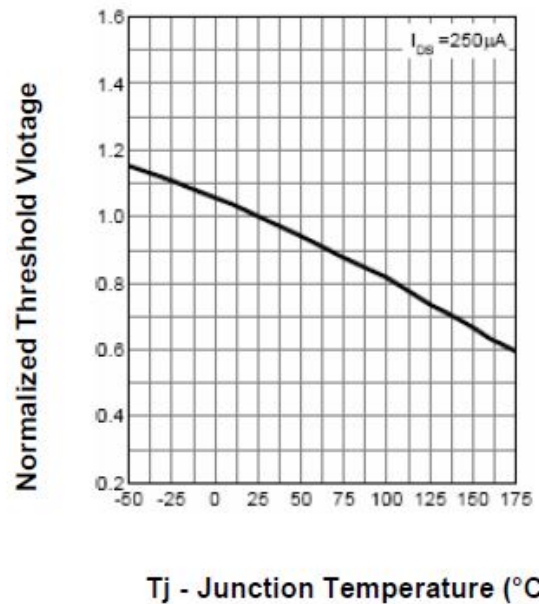
Drain-Source On Resistance



Drain-Source On Resistance

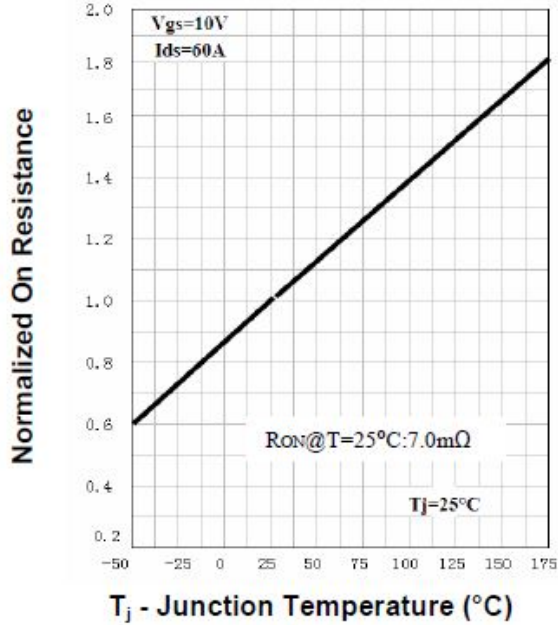


Gate Threshold Voltage

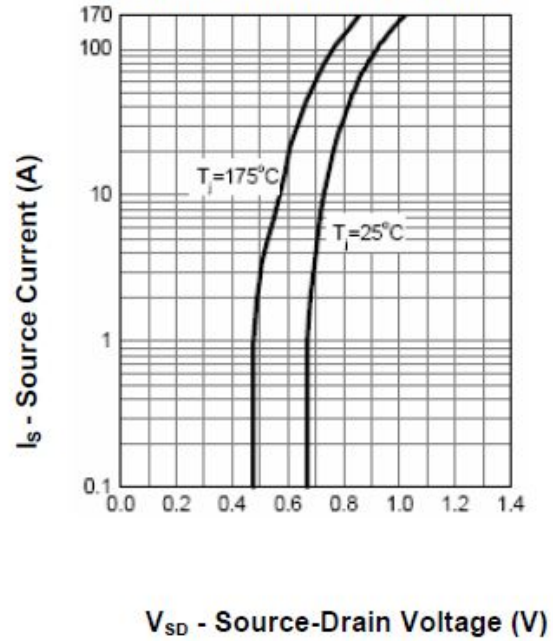


Typical Characteristics

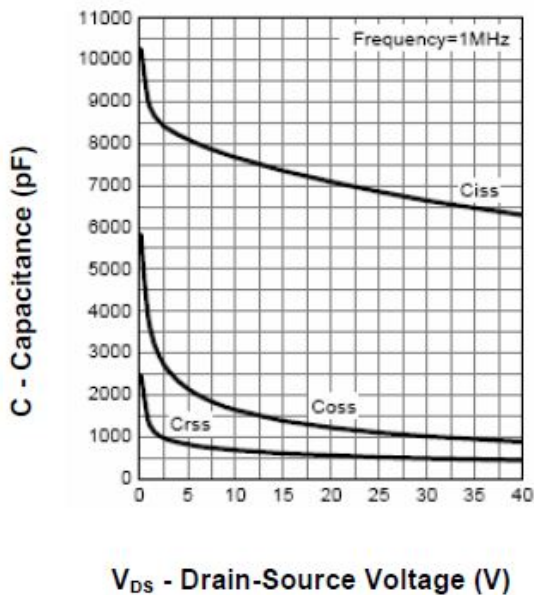
Drain-Source On Resistance



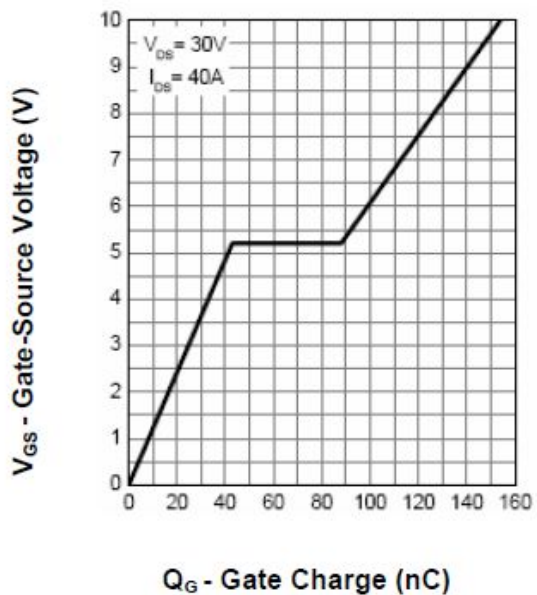
Source-Drain Diode Forward



Capacitance

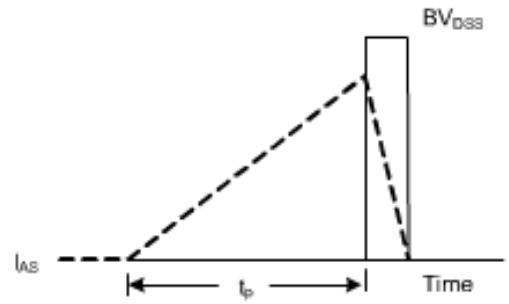
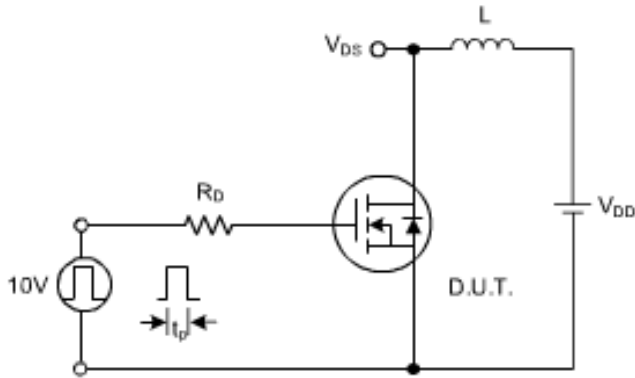


Gate Charge



Test Circuits

Avalanche test circuits and waveforms



Gate charge test circuits and waveforms

